Notice of References Cited

| Application/Control No. 10/711,472 | Applicant(s)/Patent Under Reexamination CHEN ET AL. | | |
|------------------------------------|---|-------------|--|
| Examiner | Art Unit | | |
| Russell Frejd | 2128 | Page 1 of 2 | |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|---|-----------------|---------------------|----------------|
| * | A | US-2004/0225459 | 11-2004 | Krishnaswamy et al. | 702/057 |
| | В | US- | | | |
| * | С | US-2002/0188904 | 12-2002 | Chen et al. | 714/741 |
| * | D | US-7,124,342 | 10-2006 | Wang et al. | 714/741 |
| * | E | US-6,789,223 | 09-2004 | Fetherson, R. Scott | 714/738 |
| * | F | US-6,678,645 | 01-2004 | Rajsuman et al. | 703/20 |
| * | G | US-6,453,437 | 09-2002 | Kapur et al. | 714/741 |
| | Н | US- | | | |
| | ı | US- | | | |
| | J | US- | | | |
| | К | US- | | | |
| | L | US- | | • | |
| | М | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|---|-----------------|---------|------|----------------|
| | N | | | | | |
| | 0 | | | | | |
| | Р | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | Т | | | | · | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|--|
| | U | ZARRINEH et al., K. System-on-chip testability using LSSD scan structures, IEEE Design & Test of Computers, Vol. 18, May-June 2001, pp. 83-97. |
| | ٧ | ASTROM et al., P. Application of Software design patterns to DSP library design, Proceedings of the 14th International Symposium on Systems Synthesis, September 2001, pp. 239-43. |
| | w | ZORIAN et al., Testing embedded-core-based system chips, Computer, IEEE, Vol. 32, June 1999, pp. 52-60. |
| | x | GUPTA et al., R.K. Introducing core-based system design, IEEE Design & Test of Computers, Vol. 14, OctDec. 1997, pp. 15-25. |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited Application/Control No. 10/711,472 Examiner Russell Frejd Applicant(s)/Patent Under Reexamination CHEN ET AL. Art Unit Page 2 of 2

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|---|-----------------|------|----------------|
| | Α | US- | | | |
| | В | US- | | • | |
| | С | US- | | | • |
| | D | US- | | | |
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| | F | US- | | | |
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| | l | US- | | | |
| | J | US- | | | |
| | К | US- | | | |
| | L | US- | | | |
| | М | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|---|-----------------|---------|------|----------------|
| | N | | | | | |
| | 0 | | | | | - |
| | Р | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | · | |
| | Т | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | υ | ARMSTRONG et al., J.R. VHDL Modeling and Model Testing for DSP Applications, IEEE Transactions on Industrial Electronics, Vol. 46, No. 1, February 1999, pp. 13-22. |
| | V | |
| | w | |
| | x | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.